

Notice of References Cited	Application/Control No. 10/550,842		Applicant(s)/Patent Under Reexamination CHUNG ET AL.	
	Examiner Frederick J. Parker		Art Unit 1792	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0025379	02-2002	Nakamura et al.	427/322
*	B	US-6,116,728	09-2000	Miyake et al.	347/102
*	C	US-6,153,263	11-2000	Haruta et al.	427/261
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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